

Micron Scale Pixel Hybrid Detector for Hard X-rays

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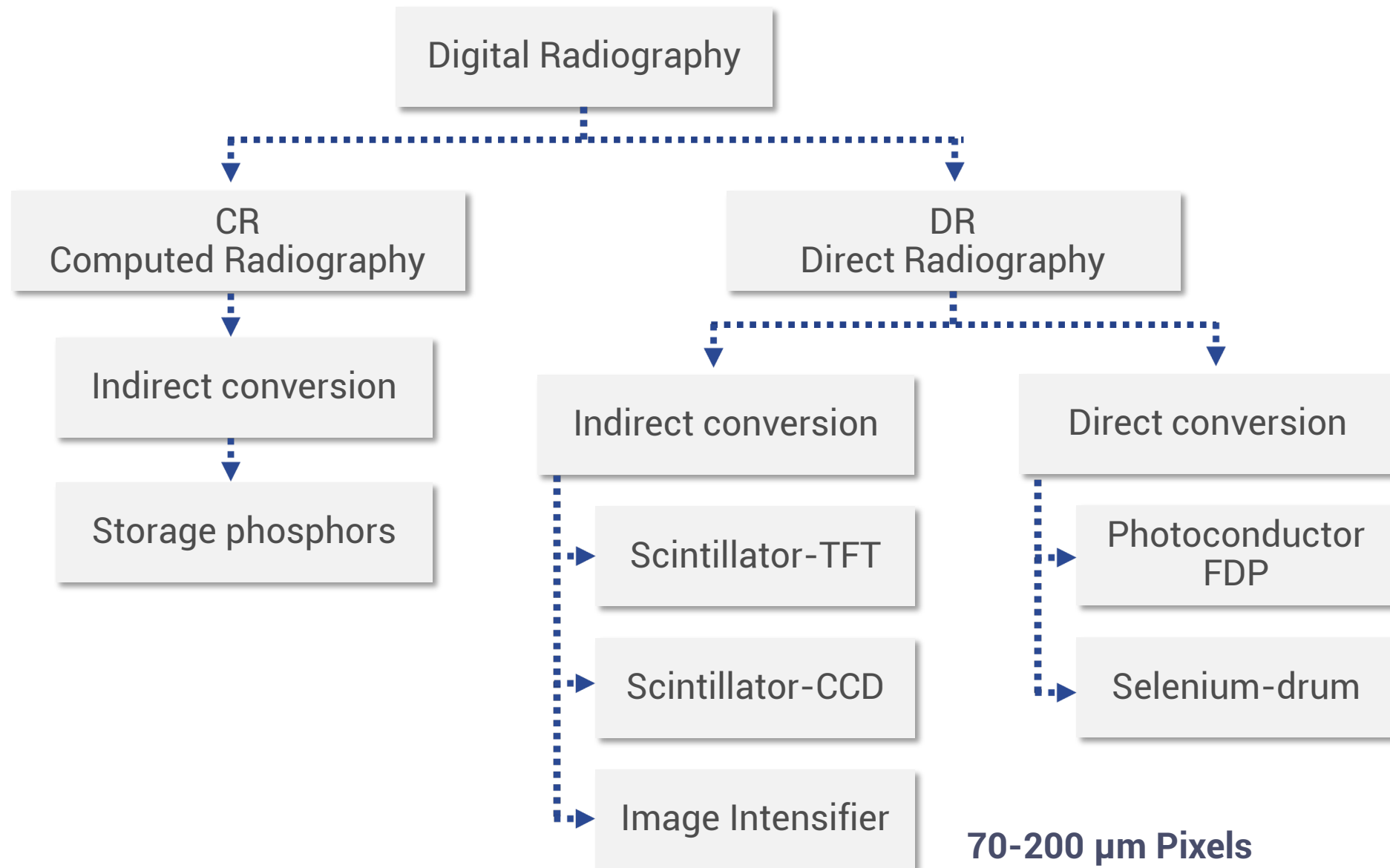
24/06/2020

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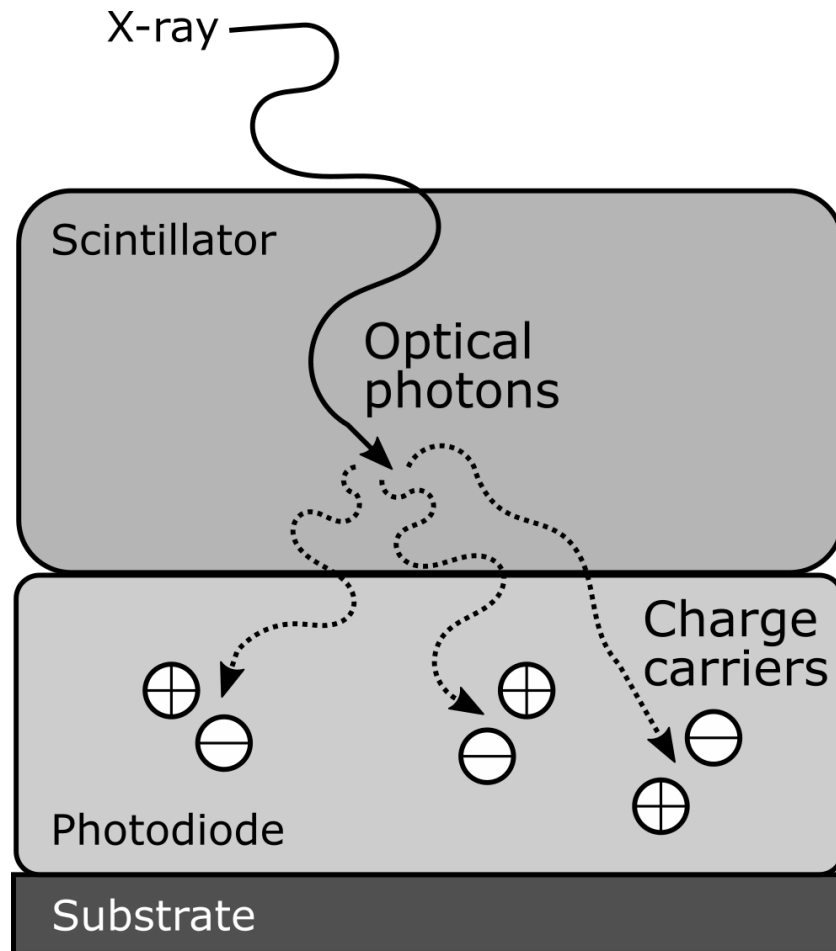
²University of Waterloo, 200 University Ave West, Waterloo, ON, Canada



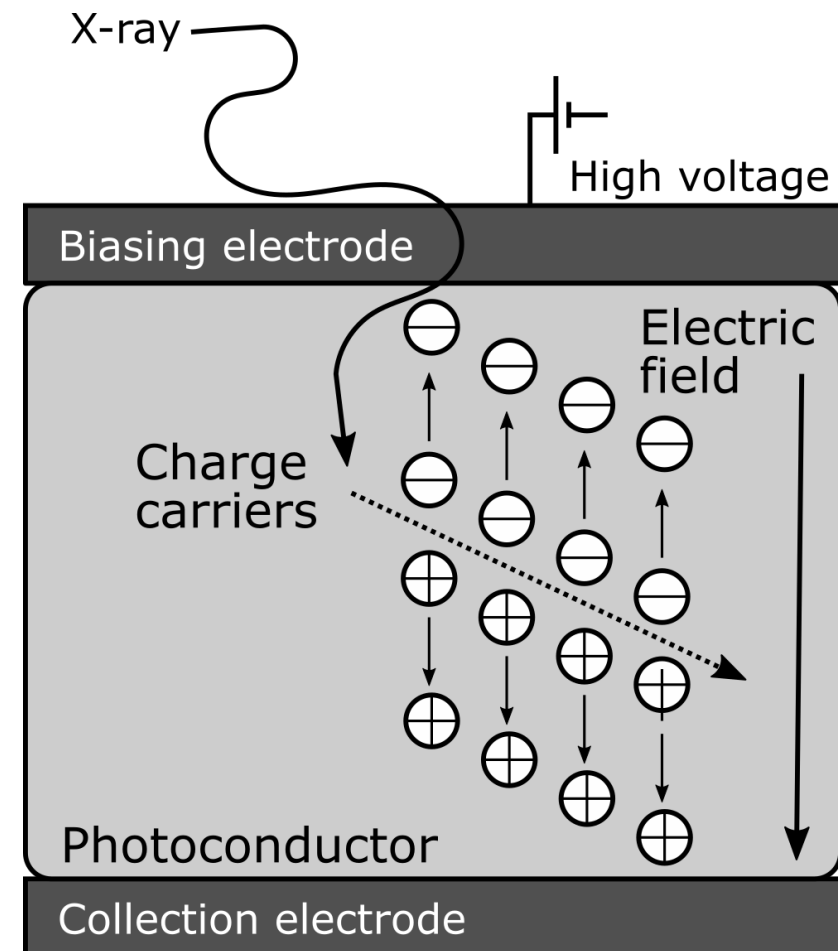
Digital Radiography



Solid-State X-ray Detection



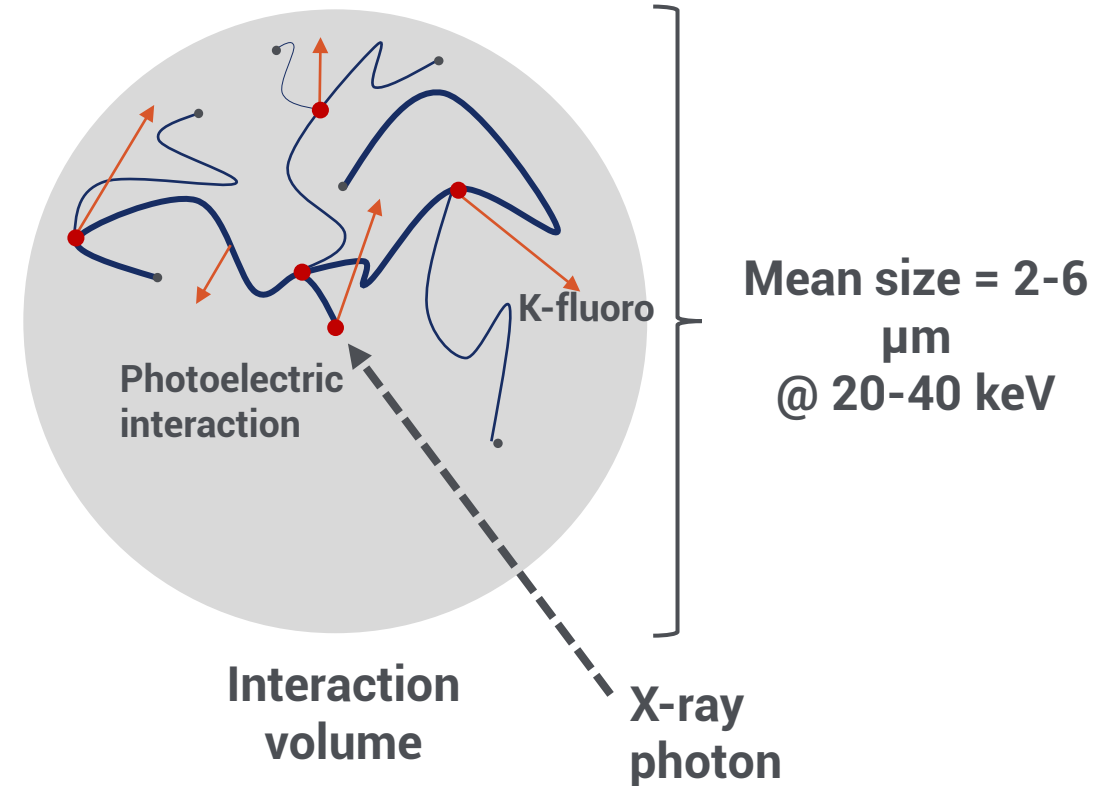
Indirect conversion



Direct conversion

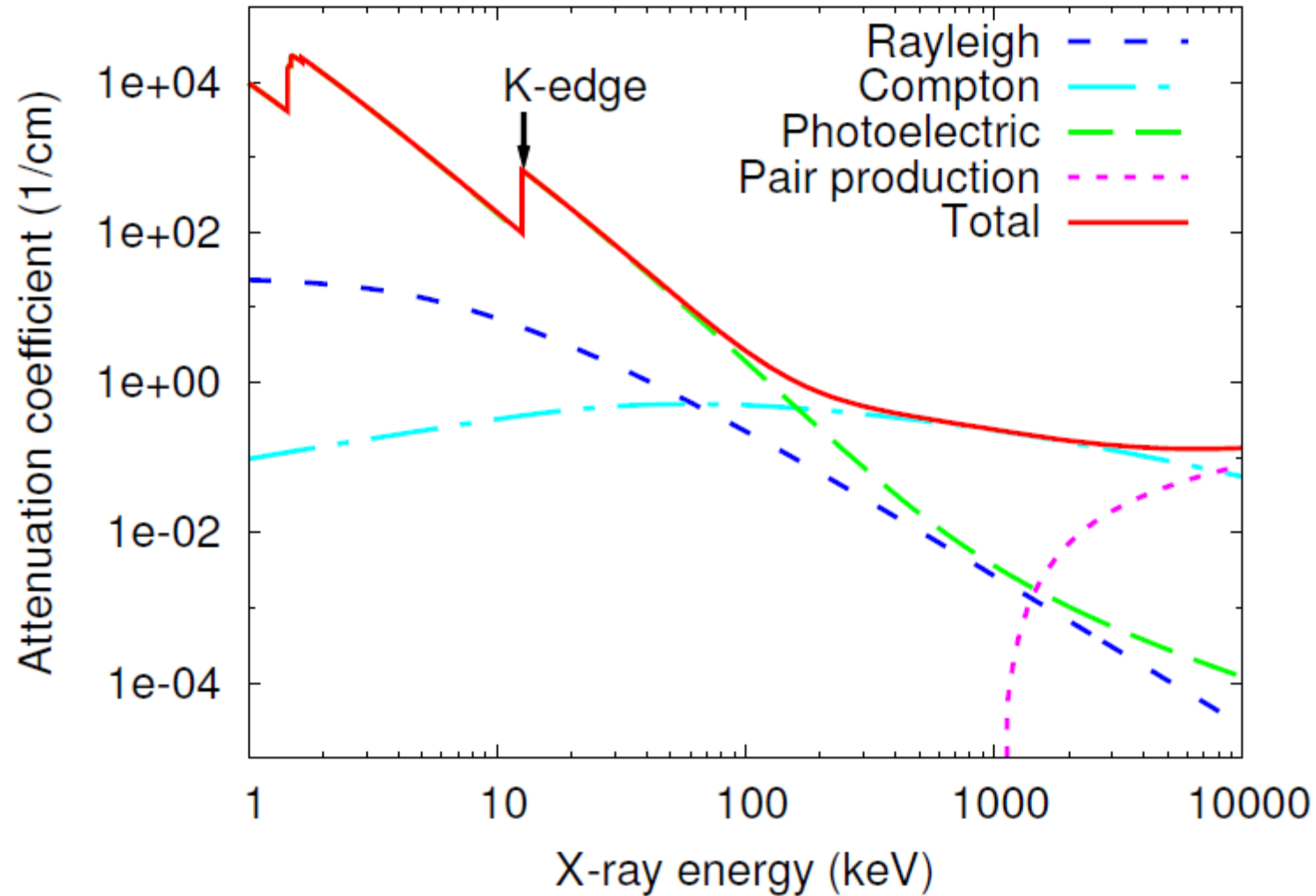
Amorphous Selenium (a-Se) Photoconductor

- Easily processed as a uniform thick layer over large area
- Atomic number (34) sufficient for hard x-ray imaging
- Low dark current & High charge collection efficiency



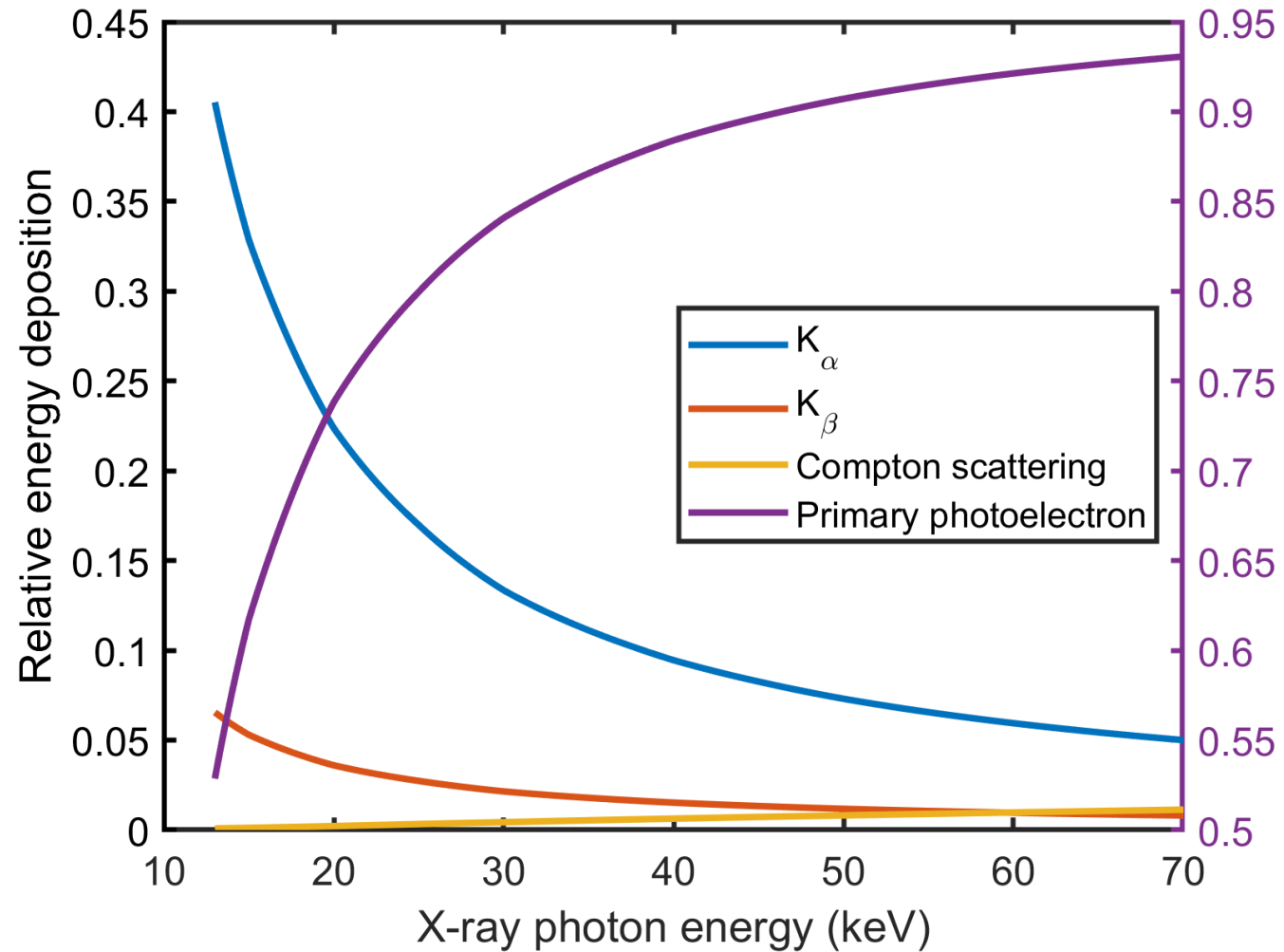
High Inherent Spatial Resolution, High Absorption for Diagnostic X-rays
→ **Low noise, Small Pixel Pitch CMOS**

X-ray Attenuation Coefficients for a-Se



K-edge = 12.66 keV

X-ray Interaction Energy Deposition in a-Se



35 keV

$$p_{pe} = 0.866$$

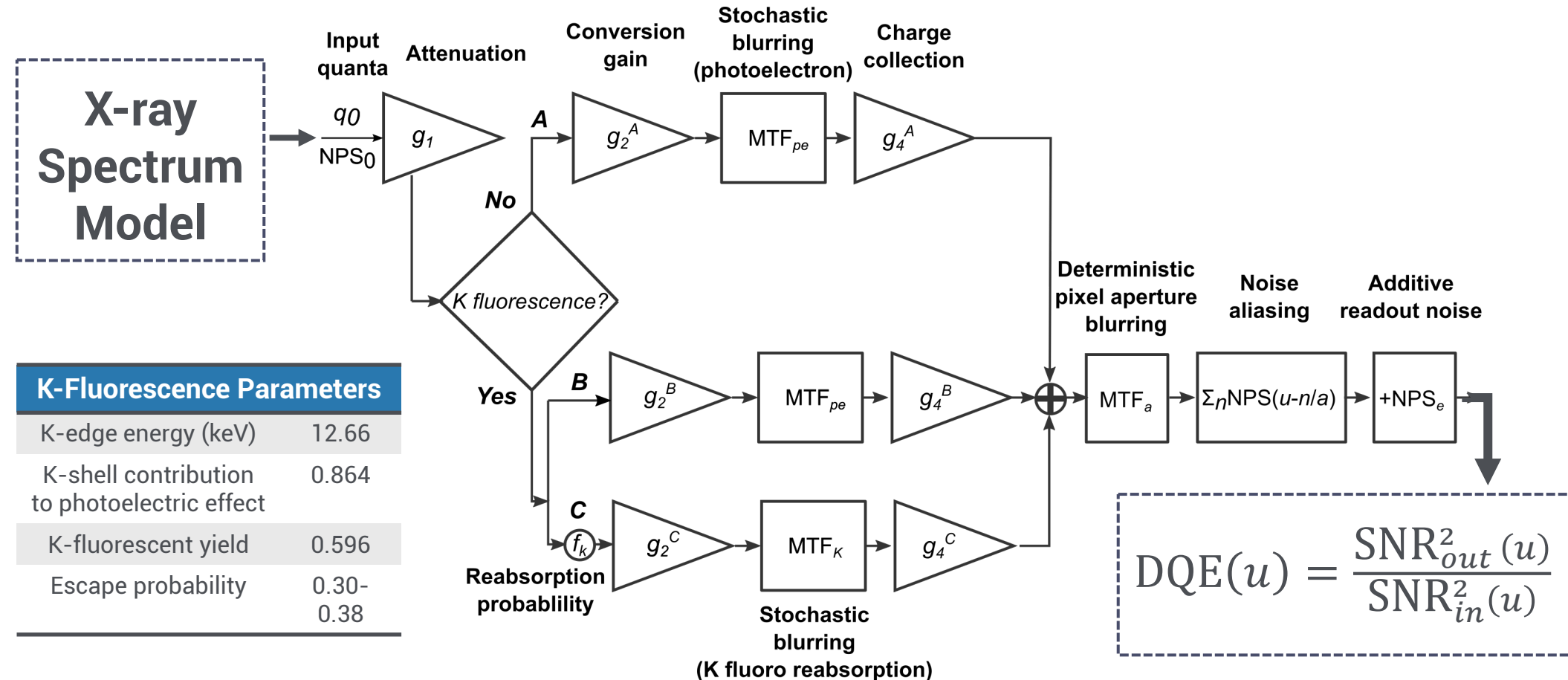
$$p_{K_{\alpha}} = 0.111$$

$$p_{K_{\beta}} = 0.018$$

$$p_C = 0.005$$

Weighting Factors

Cascaded Systems Theory

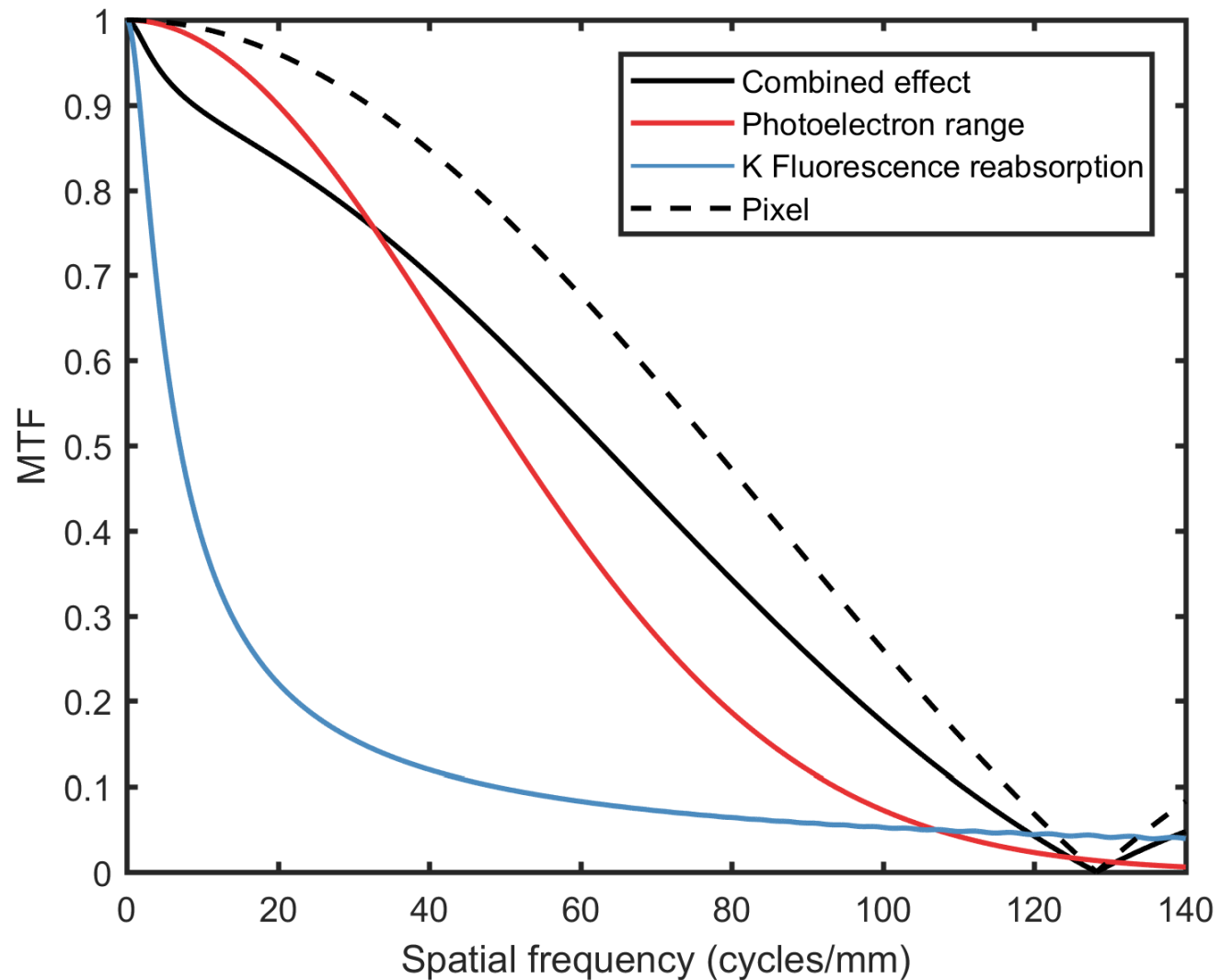


K-Fluorescence Parameters

K-edge energy (keV)	12.66
K-shell contribution to photoelectric effect	0.864
K-fluorescent yield	0.596
Escape probability	0.30-0.38

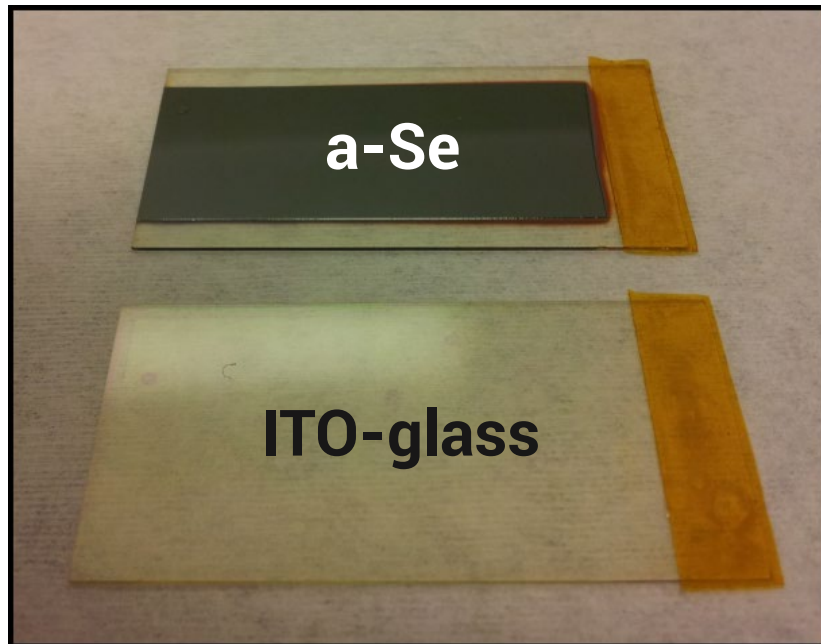
Detective Quantum Efficiency (DQE)

X-ray Interaction MTF for a-Se



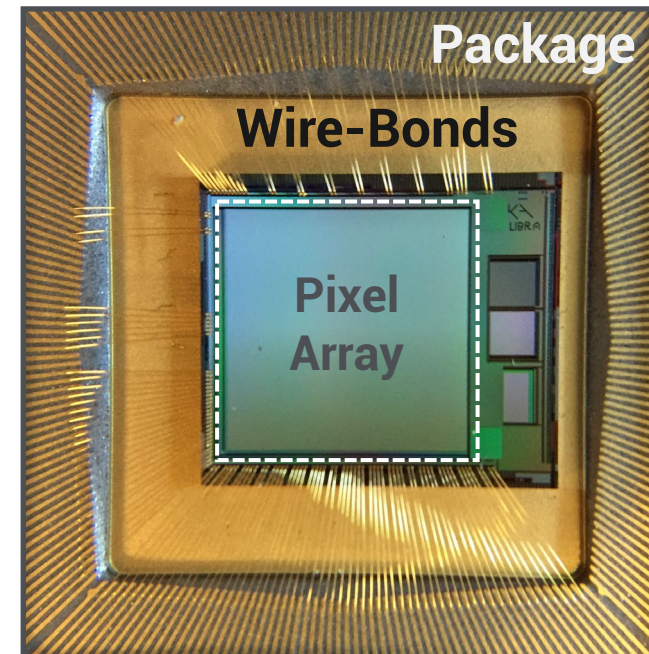
Objective

Develop hybrid **a-Se/CMOS detectors** to achieve a unique combination of high spatial resolution ($\leq 10 \mu\text{m}$ pixel) and high quantum efficiency for hard x-rays for **X-ray diffraction imaging**



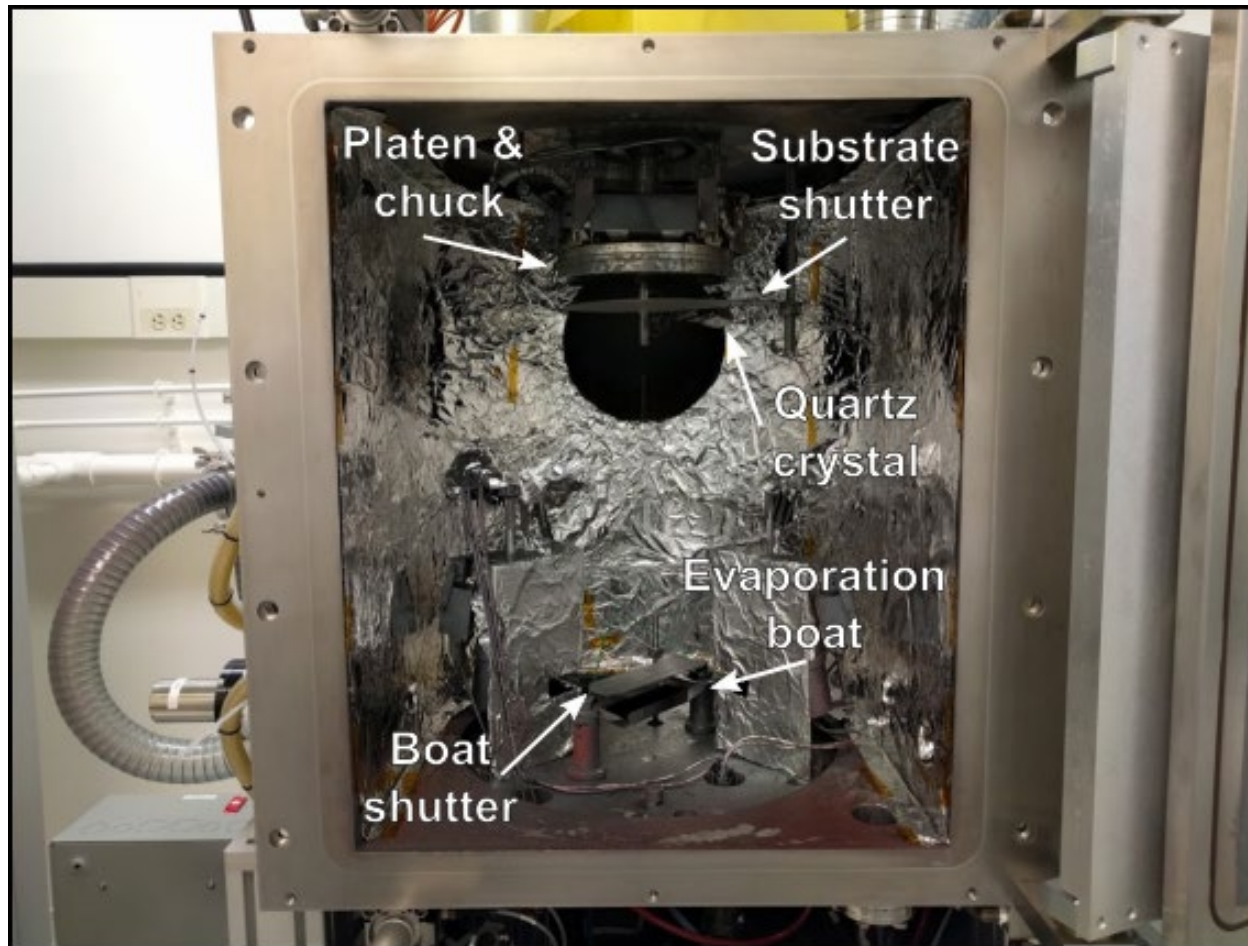
**a-Se Films on ITO-glass
by Physical Vapor
Deposition**

+

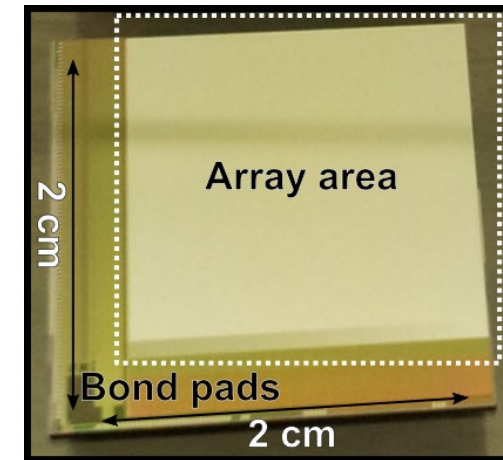


**CMOS Readout
Integrated Circuit (ROIC)**

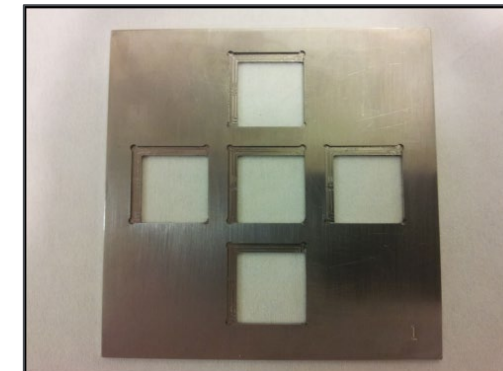
Deposition of a-Se Films by Thermal Evaporation



**Thermal Evaporator for a-Se
at G2N Centre, University of Waterloo**

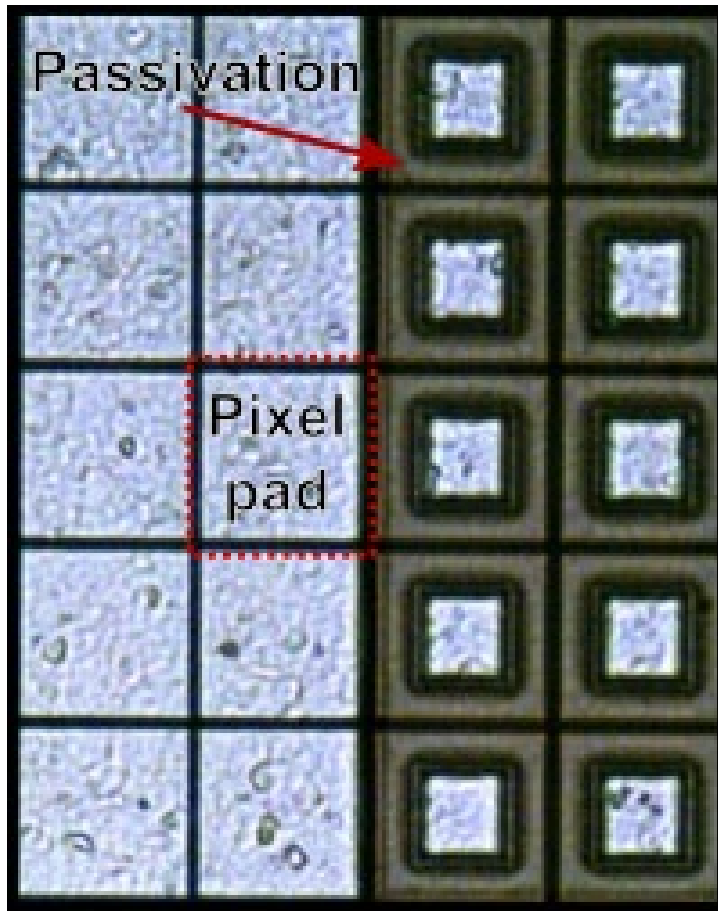


CMOS Readout IC

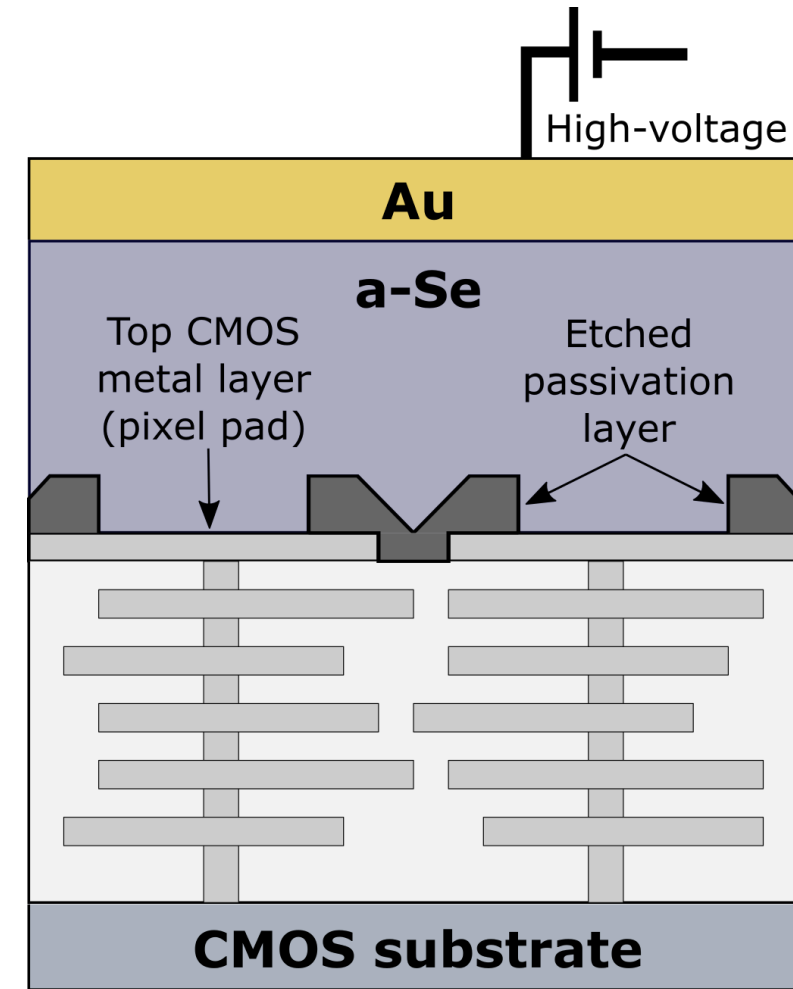


Shadow Mask

Back-end Processing of CMOS ROIC

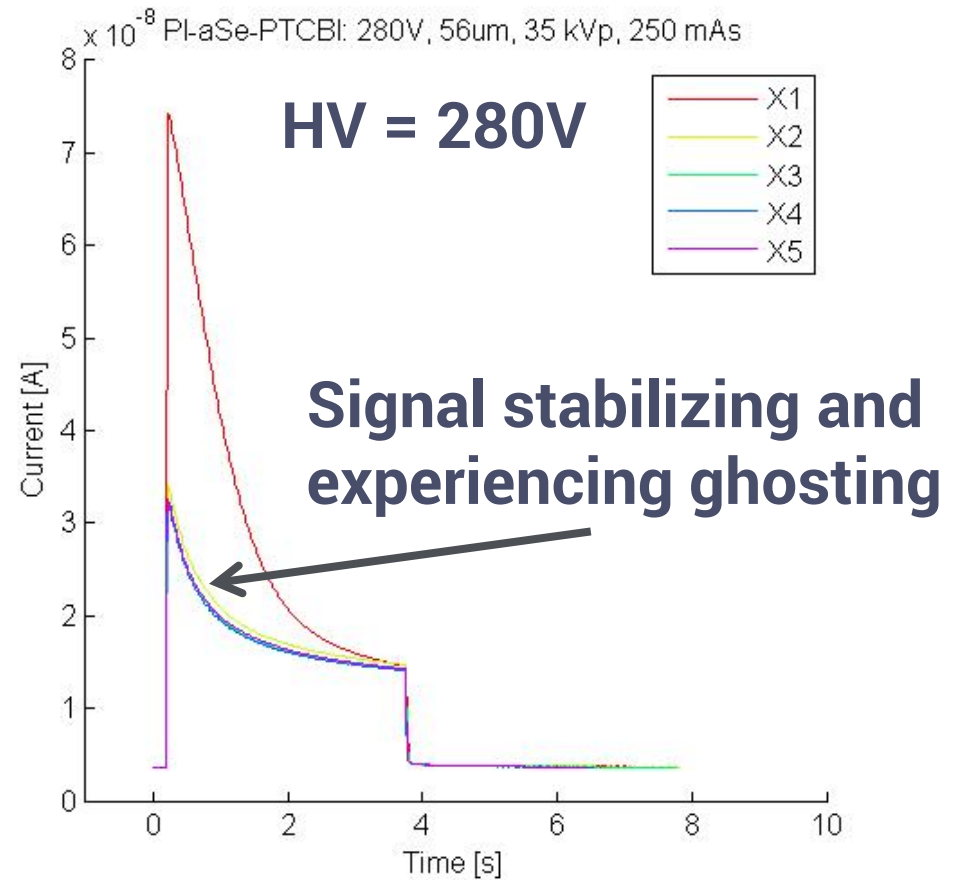
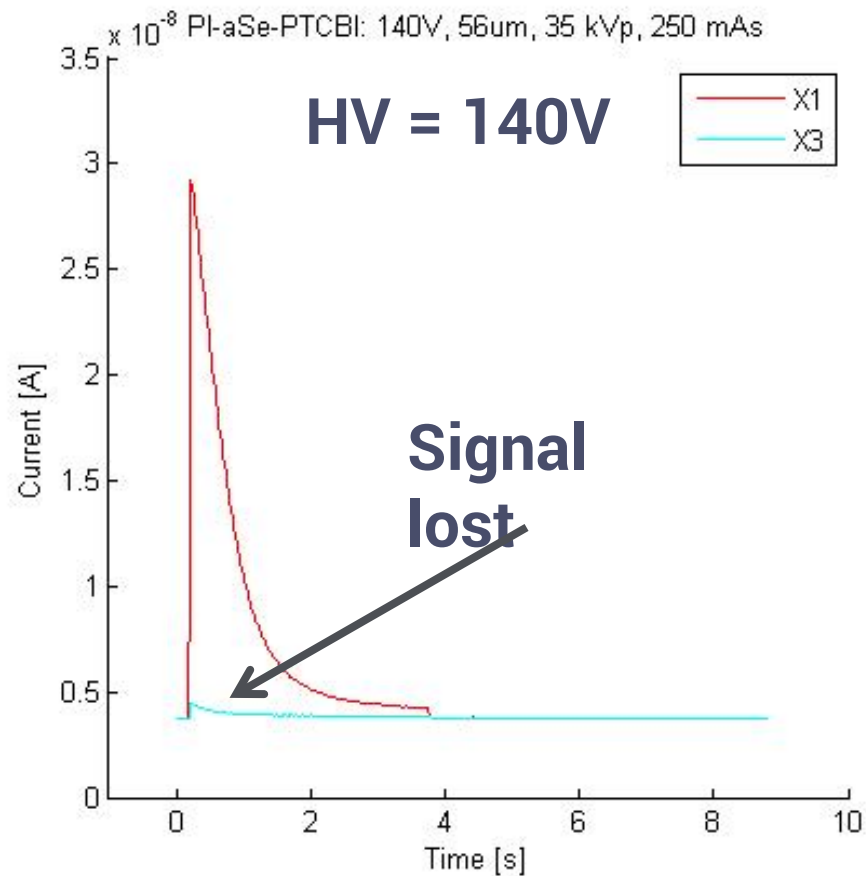


A micrograph of etched CMOS passivation



A diagram of the a-Se/CMOS detector cross-section

Polyimide Layer Conduction

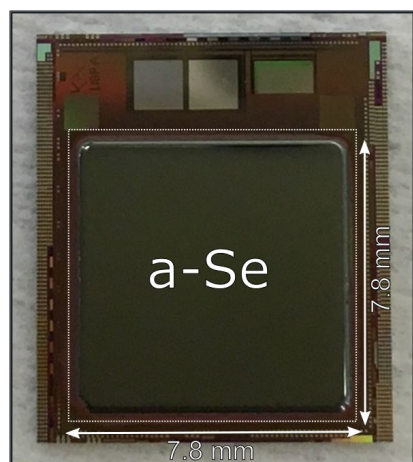


35 kVp, 250 mAs
1 min. between exposures
5 min. between HV changes)

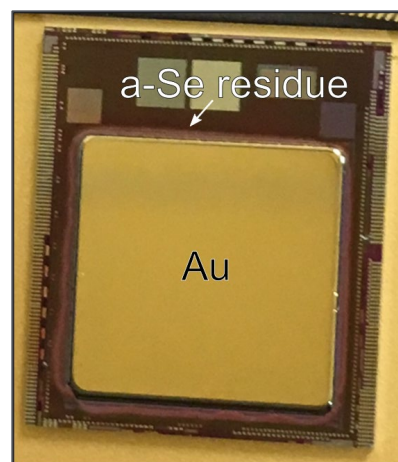
- Charge build-up at the a-Se/PI \rightarrow E-field reduction \rightarrow sensitivity loss
- Reversing the detector bias resets the device.

LIBRA Readout IC

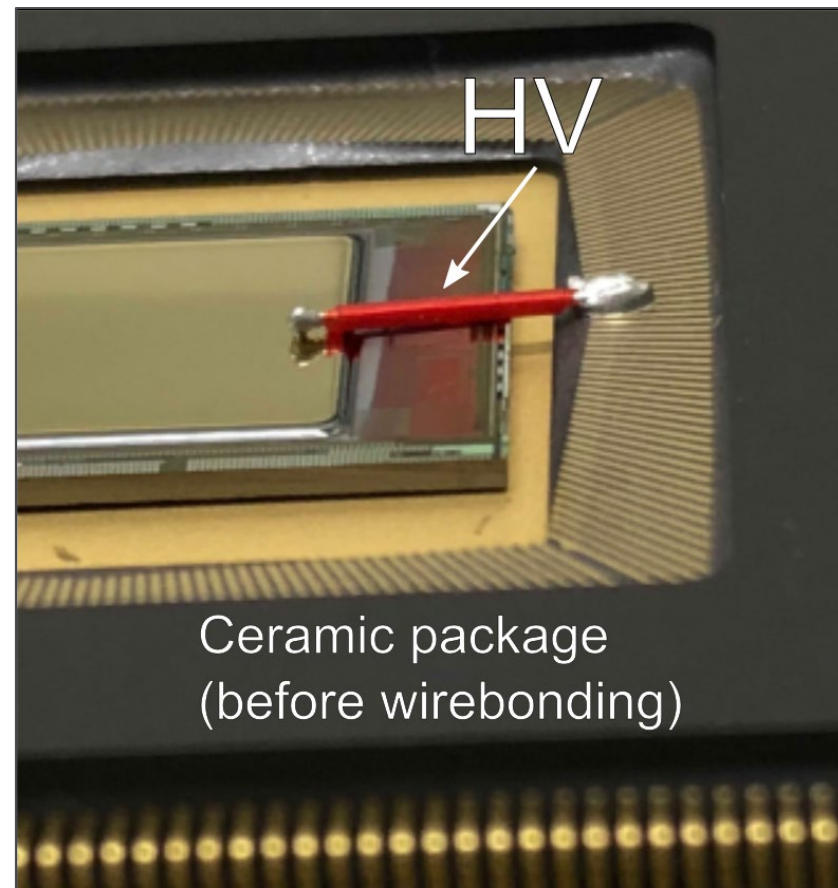
- 3T active pixel sensor
- $7.8 \times 7.8 \mu\text{m}^2$ pixel pitch
- 1000×1000 pixel array
- $7.8 \times 7.8 \text{ mm}^2$ imaging area



a-Se Deposition

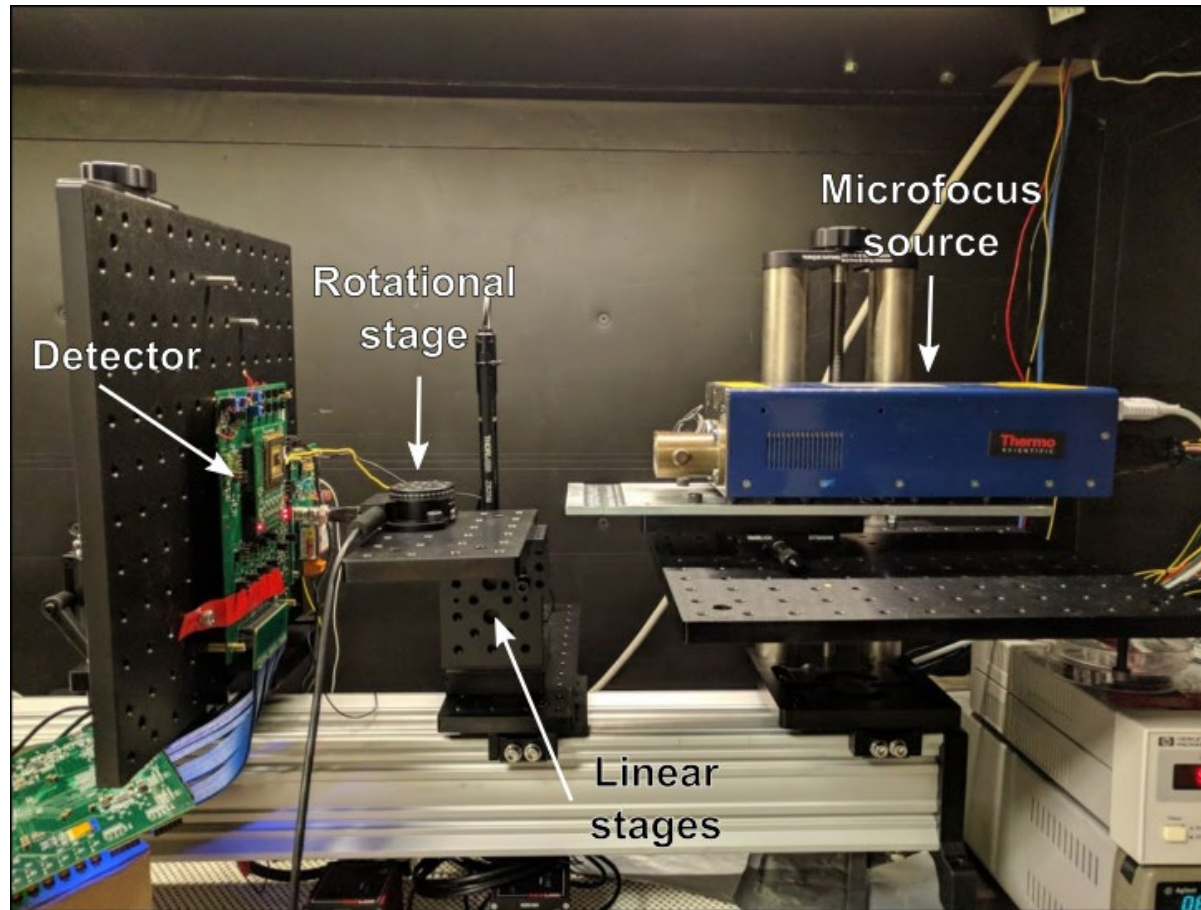


Au Deposition

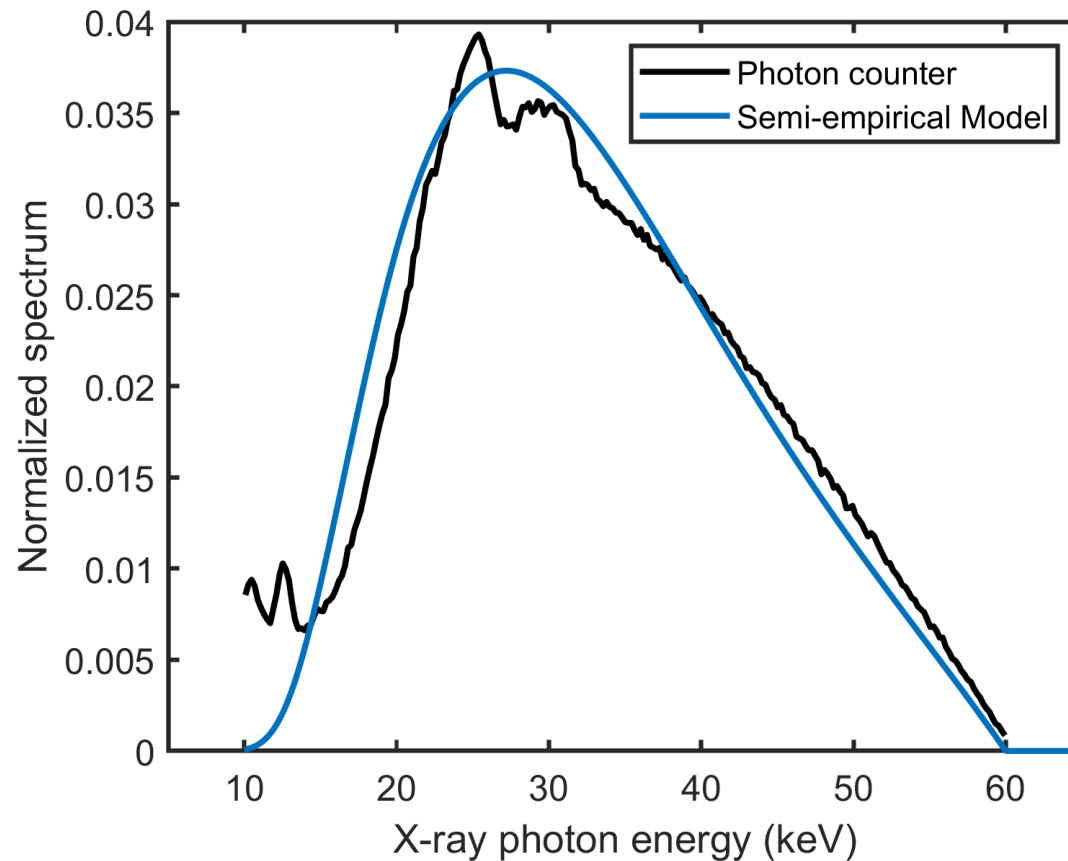


Packaging

LIBRA @ University of Waterloo



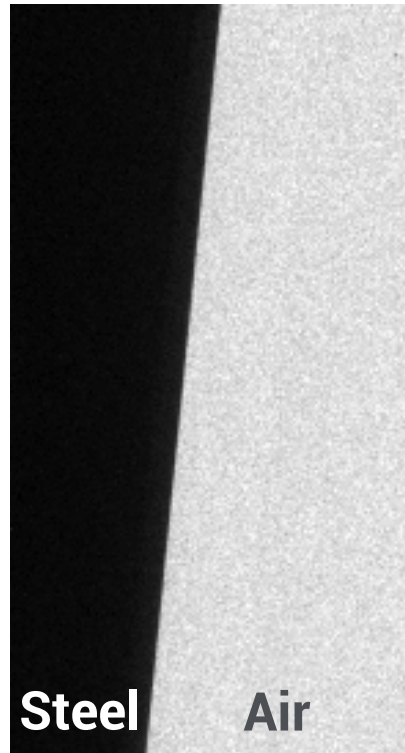
Microfocus Spectrum Characterization



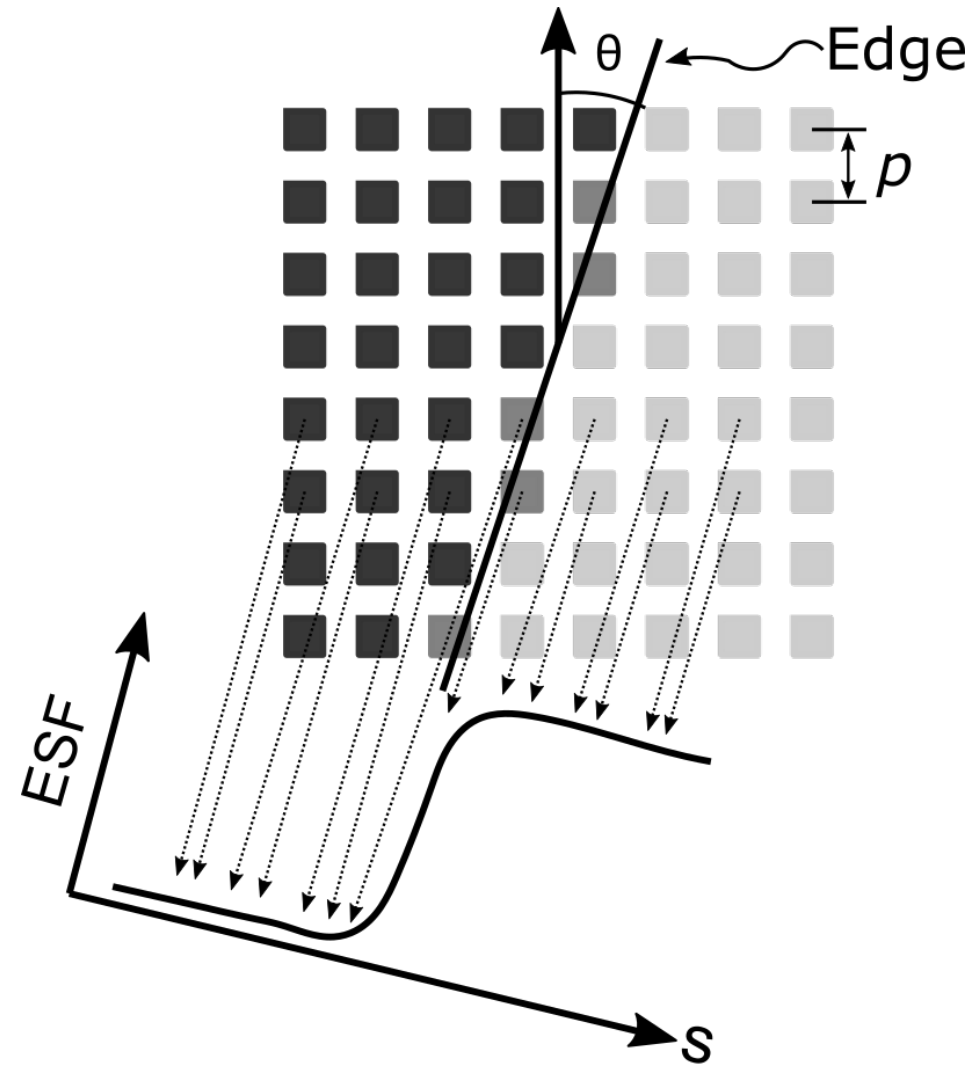
9 μm spot size

Tube potential (kV)	60
Filter (mm Al)	3.0
Half-value-layer (mm Al)	1.69
Mean Energy (keV)	34.3
Fluence per Exposure ($\text{mm}^{-2} \text{R}^{-1}$)	1.26×10^8

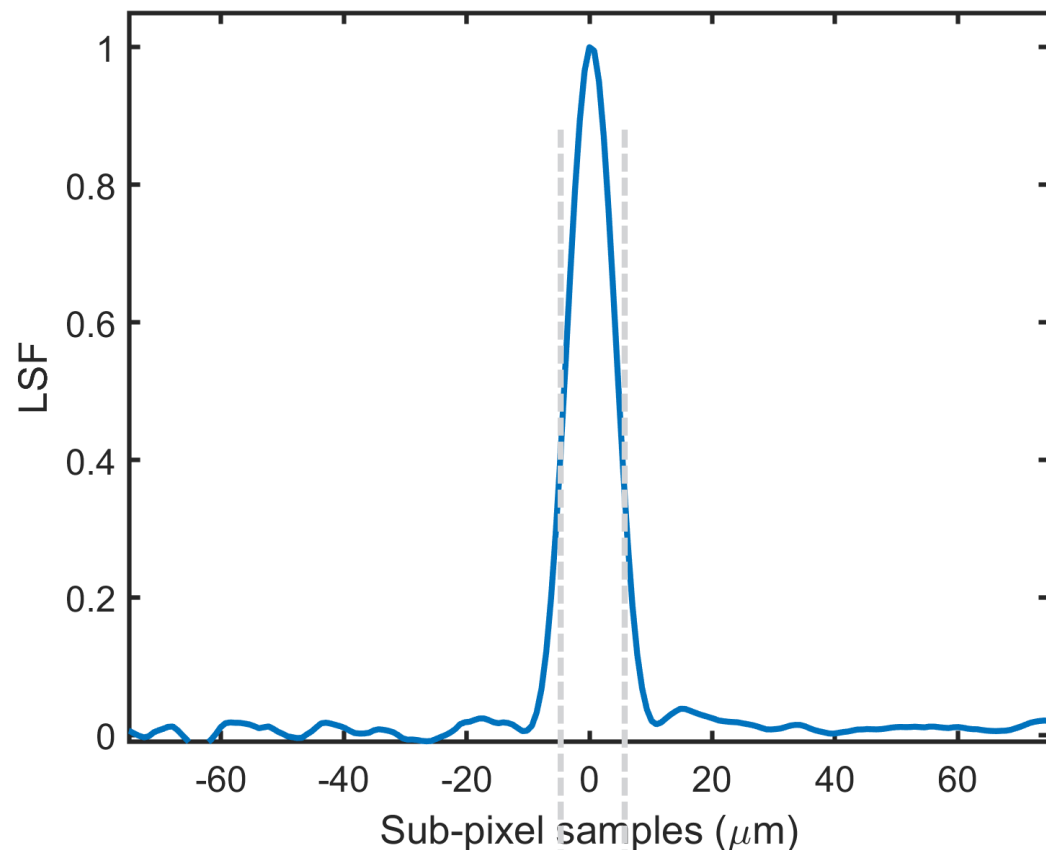
Slanted-Edge Technique



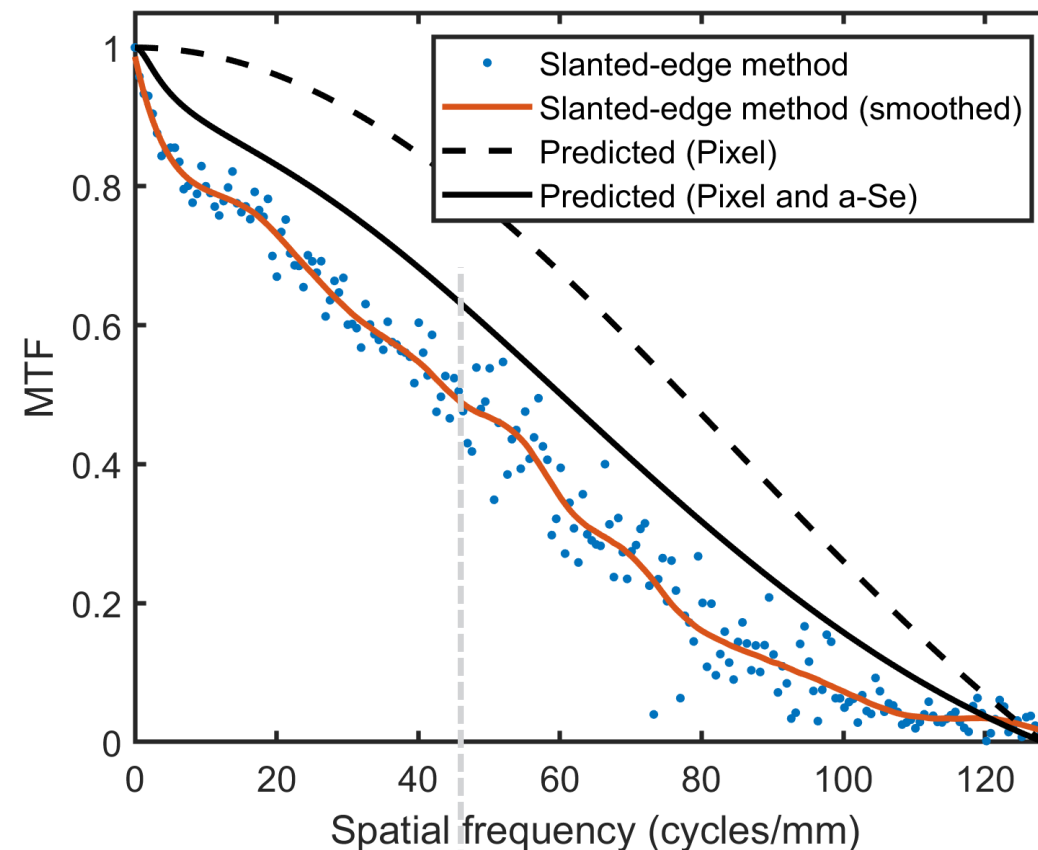
Edge image



LIBRA Spatial Resolution



FWHM = 9.7 μm



50% contrast for 11 μm object

High Resolution Scintillator Comparison:
15 μm GADOX 9 μm pixel FWHM = 27 μm

Larsson et al., Scientific Reports 6, 2016

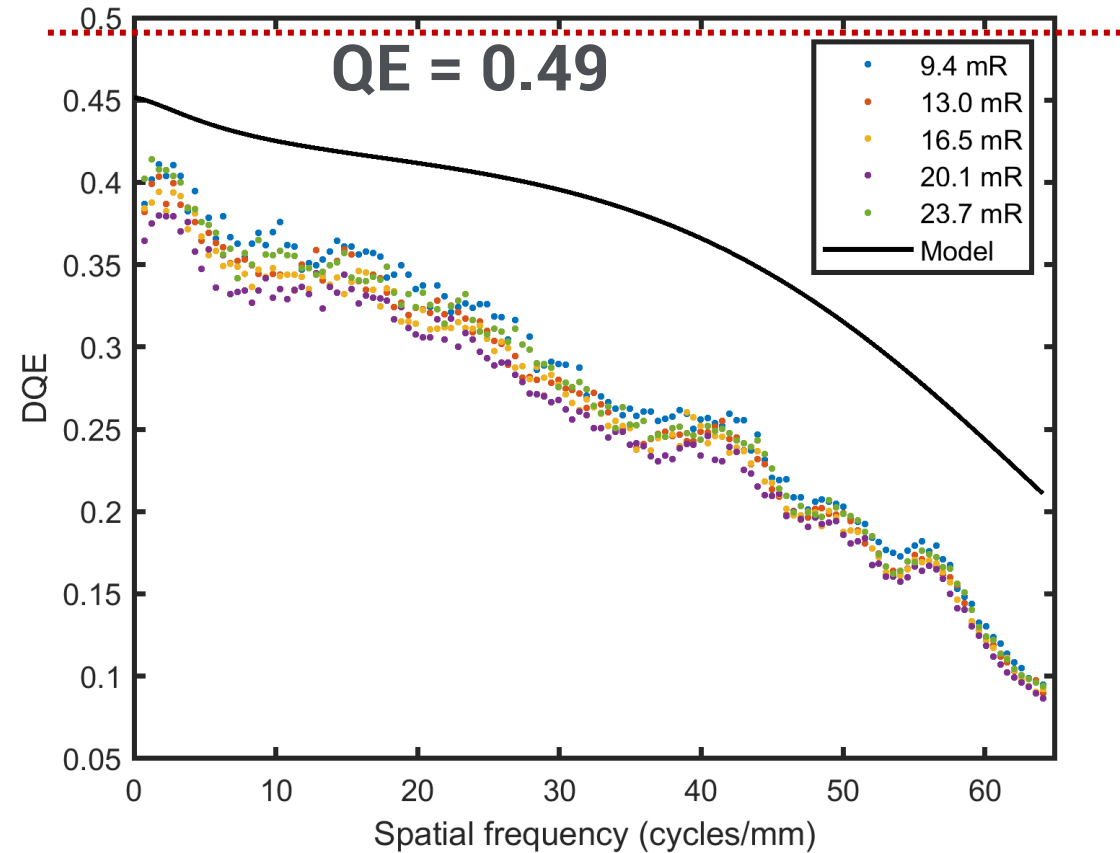
LIBRA DQE

Best reported to date:

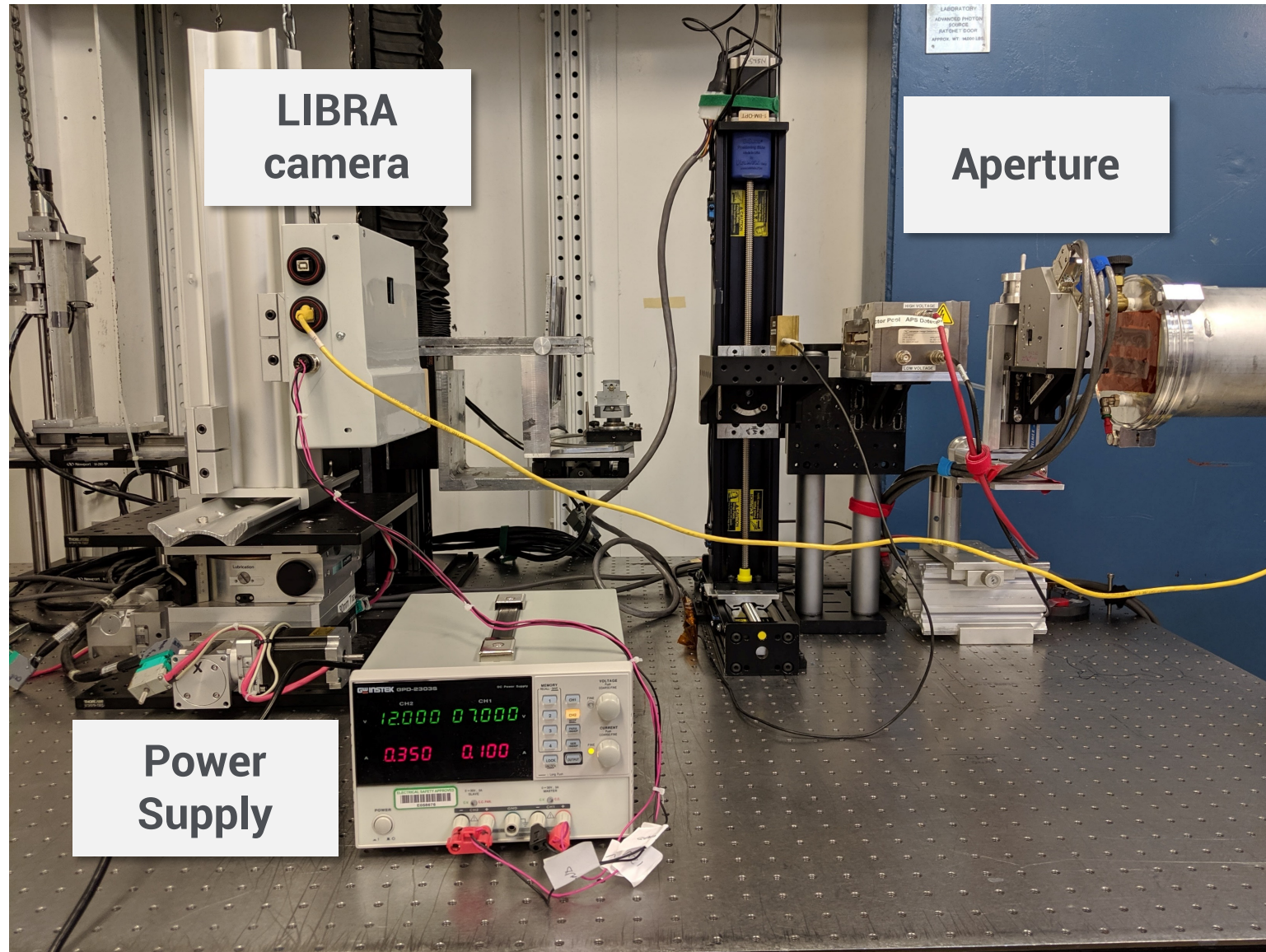
15 μm GADOX
9 μm pixel
QE = 0.13

*Larsson et al., Scientific
Reports 6, 2016*

Vs

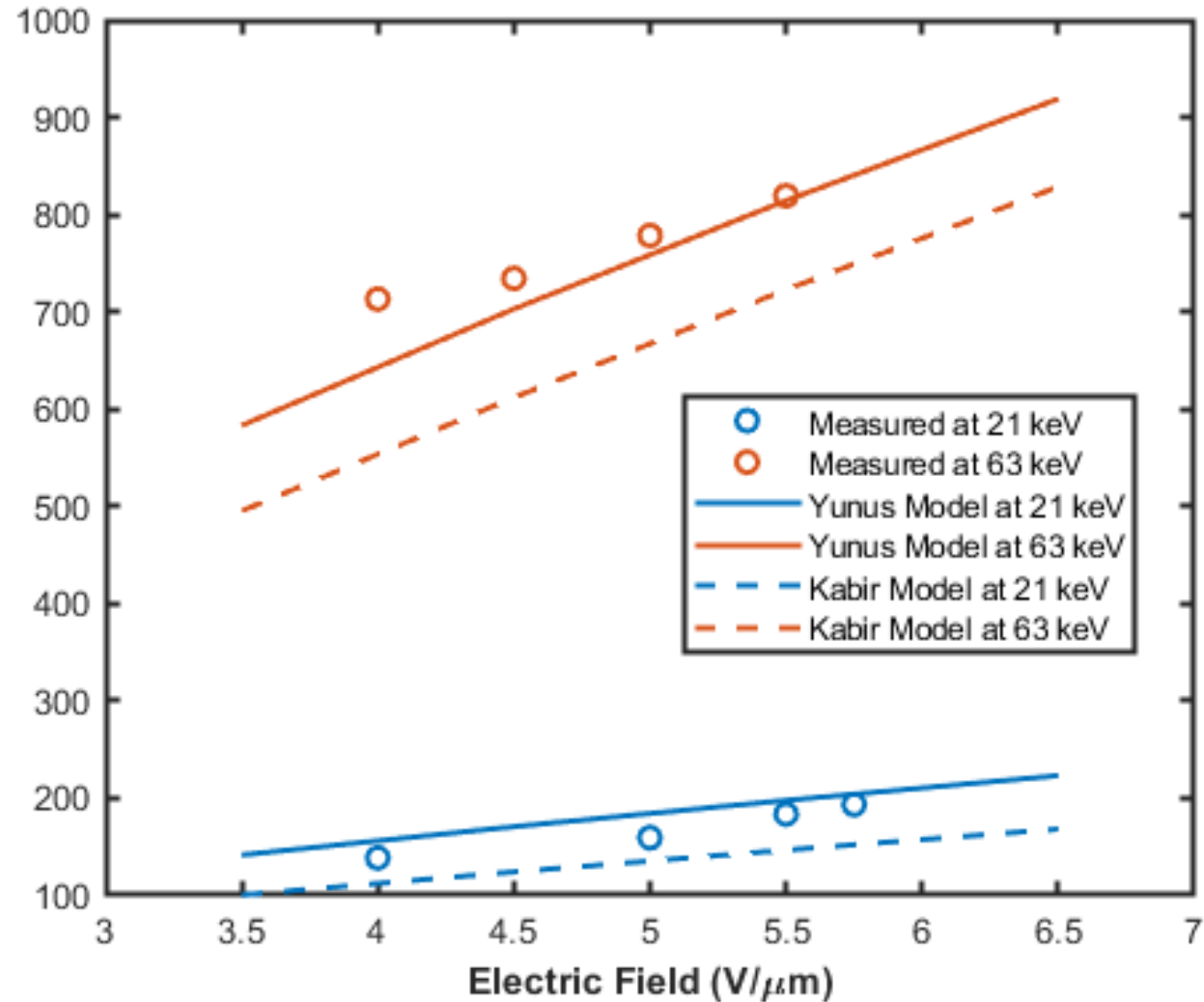
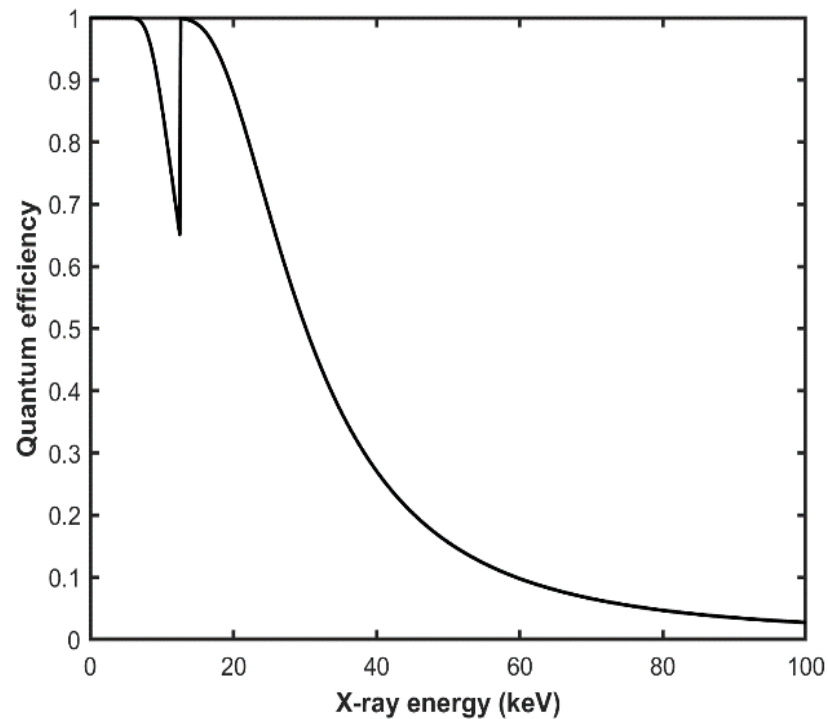


LIBRA @ ANL APS Beamline 1-BM

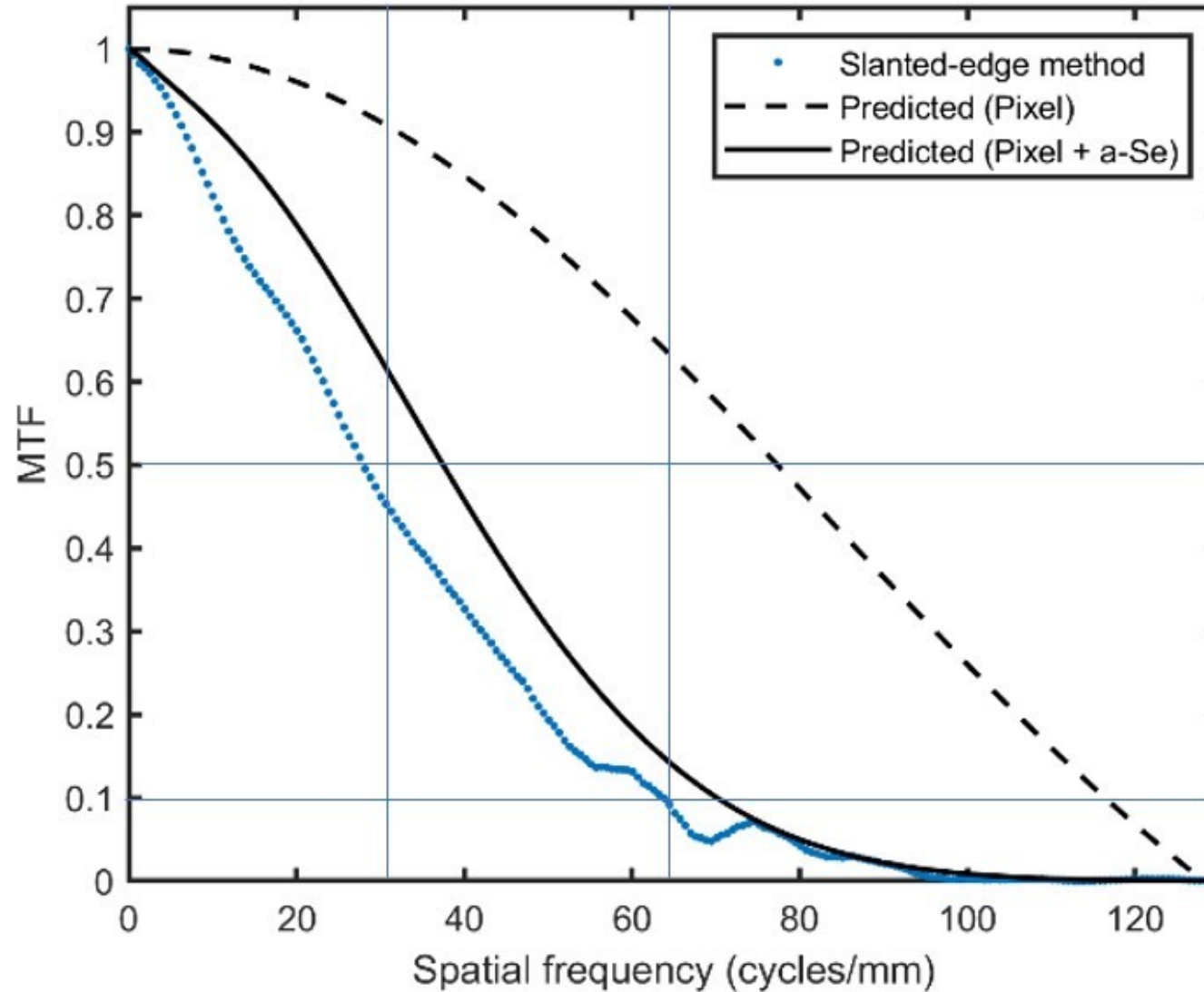


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LIBRA Responsivity @ 21 keV and 63 keV

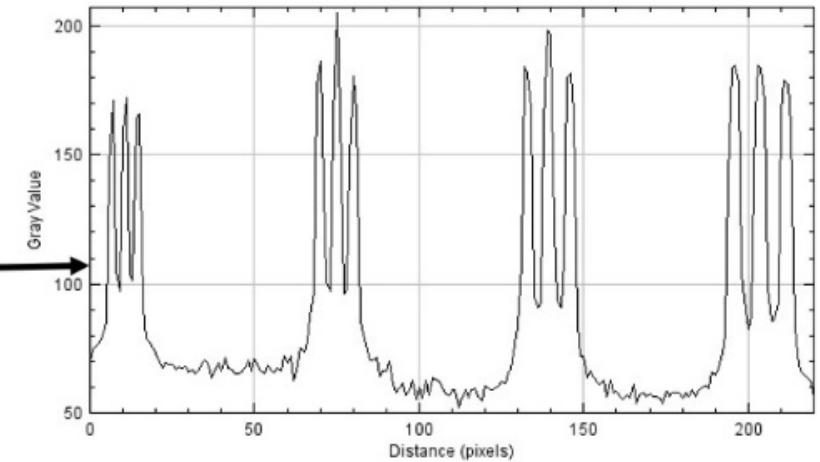
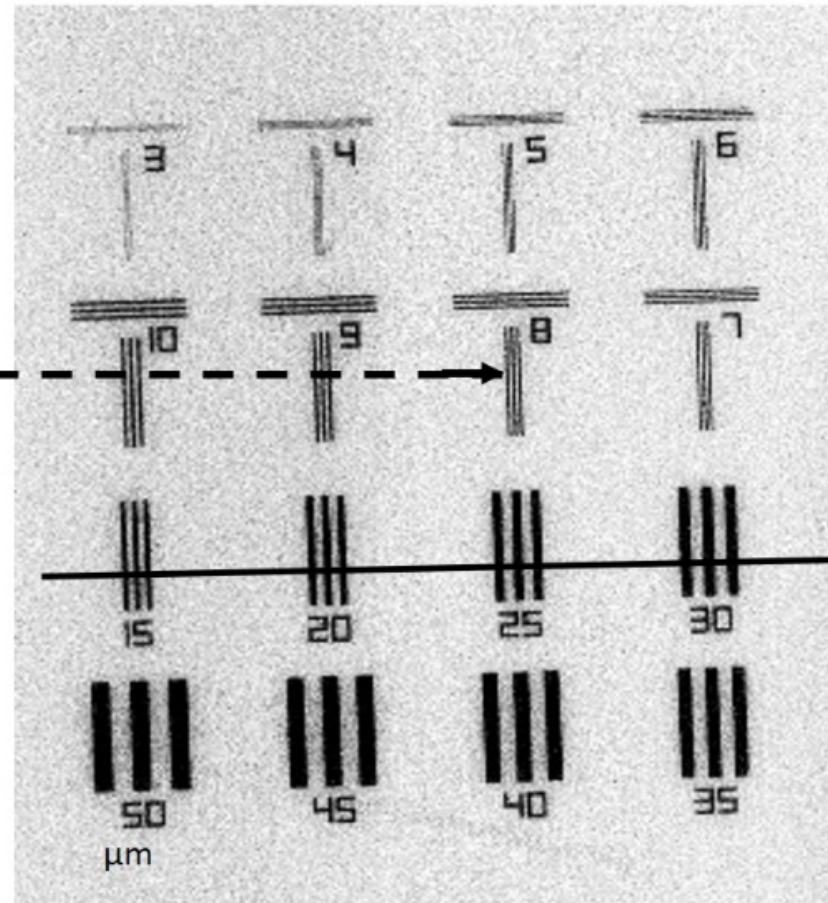
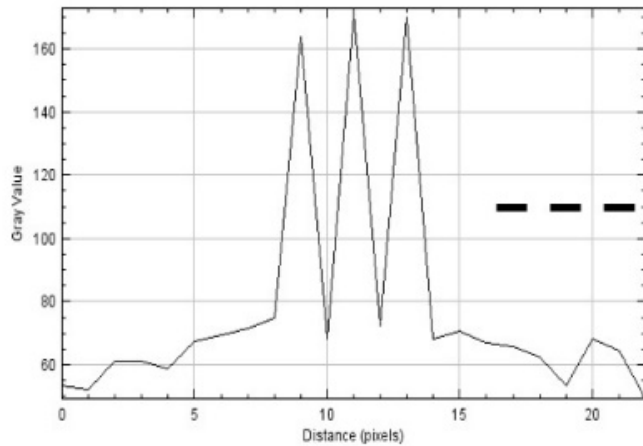


LIBRA Spatial Resolution @ 63 keV



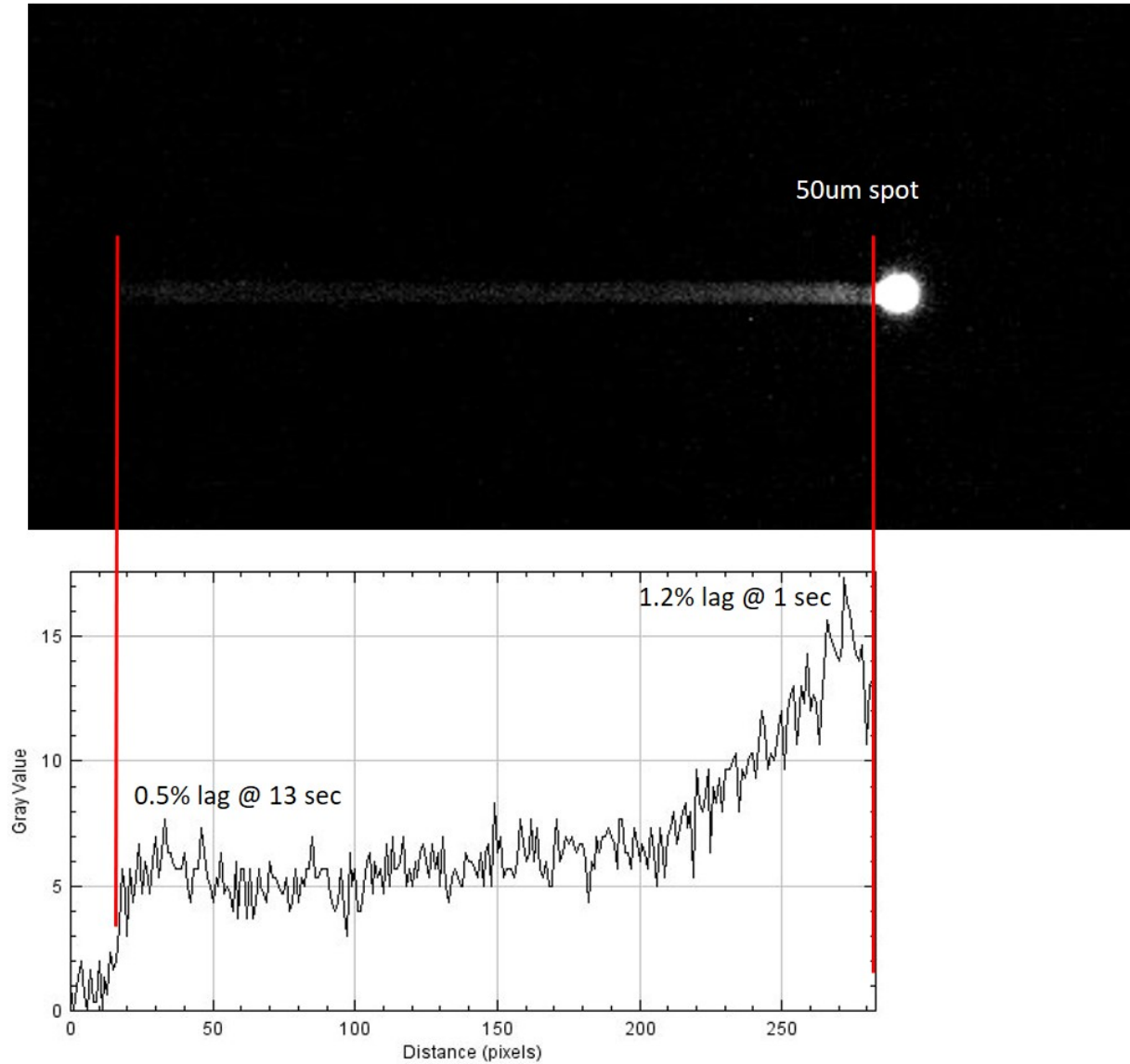
JIMA RT RC-05 Transmission Bar Target @ 21 keV

JIMA RT RC-05 Image _21keV_100fr avg_250ms Tint



50 μm Pinhole Lag @ 63 keV

Scanning Pin Hole _ 63 KeV_ Scan Rate = 25.6 pix/sec



Conclusions

- The a-Se/CMOS prototypes demonstrate a remarkable combination of high spatial resolution and high quantum efficiency for hard x-rays

Factor of 3x DQE improvement despite being relatively unoptimized

Acknowledgements

Michael Farrier

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Thank you



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